

PI6CV855

PLL Clock Driver for 2.5V SSTL_2 DDR SDRAM Memory

Features

- PLL clock distribution optimized for SSTL_2 DDR SDRAM applications.
- Distributes one differential clock input pair to five differential clock output pairs.
- Inputs (CLK, CLK) and (FBIN, FBIN): SSTL_2
- Outputs (Yx, \overline{Yx}) , (FBOUT, FBOUT): SSTL_2
- External feedback pins (FBIN, FBIN) are used to synchronize the outputs to the input clocks.
- Operates at $AV_{DD} = 2.5V$ for core circuit and internal PLL, and $V_{DDQ} = 2.5V$ for differential output drivers
- Packaging (Pb-free & Green available): -28-pin TSSOP(L)

Description

PI6CV855 PLL clock device is developed for SSTL_DDR SDRAM applications. This PLL Clock Buffer is designed for 2.5 V_{DDQ} and 2.5V AV_{DD} operation and differential data input and output levels. The device is a zero delay buffer that distributes a differential clock input pair (CLK, \overline{CLK}) to five differential pairs of clock outputs (Y[0:4], $\overline{Y[0:4]}$) and one differential pair feedback clock outputs (FBOUT, FBOUT). The clock outputs are controlled by the input clocks (CLK, \overline{CLK}), the feedback clocks (FBIN, FBIN), and the Analog Power input (AV_{DD}). When the AV_{DD} is strapped low, the PLL is turned off and bypassed for test purposes.

The PI6CV855 is able to track Spread Spectrum Clocking to reduce EMI.

Block Diagram



Pin Configuration





Pinout Table

| Pin Name | Pin No. | I/O Type | Description |
|------------------|---------------|-------------|---|
| CLK CLK | 5 6 | Ι | Reference Clock input |
| Y[0:4] | 3,11,13,17,27 | | Clock outputs. |
| ¥[0:4] | 2,10,14,16,28 | 0 | Complement Clock outputs. |
| FBOUT FBOUT | 23 24 | | Feedback output, and Complement Feedback Output |
| FBIN FBIN | 21 20 | Ι | Feedback input, and Complement Feedback input |
| V _{DDQ} | 4,12,18,22,26 | | Power Supply for I/O pins. |
| AV _{DD} | 7 | Power | Analog/core power supply. AV_{DD} can be used to bypass the PLL for testing purposes. When AV_{DD} is strapped to ground, PLL is bypassed & CLK is buffered directly to the device outputs. |
| AGND | 8 | Ground | Analog/core ground. Provides the ground reference for the analog/core circuitry |
| GND | 1,9,15,19,25 | SIGUR | Ground for I/O pins. |

Function Table

| - | Outputs | | | | PLL State | | |
|------------------|---------|-----|--------|---------------|-----------|-------|--------------|
| AV _{DD} | CLK | CLK | Y[0:4] | <u>Y[0:4]</u> | FBOUT | FBOUT | |
| GND | L | Н | L | Н | L | Н | Bypassed/Off |
| GND | Н | L | Н | L | Н | L | Bypassed/Off |
| 2.5V(nom) | L | Н | L | Н | L | Н | on |
| 2.5V(nom) | Н | L | Н | L | Н | L | on |



Absolute Maximum Ratings (Over operating free-air temperature range)

| Symbol | Parameter | Min. | Max. | Units |
|-------------------------------------|---|-------|---------------|-------|
| V _{DDQ} , AV _{DD} | I/O supply voltage range and analog/core supply voltage range | - 0.5 | 3.6 | |
| VI | Input voltage range | - 0.5 | V | V |
| Vo | Output voltage range | - 0.5 | $V_{DDQ}+0.5$ | |
| Tstg | Storage temperature | - 65 | 150 | °C |

Note: Stress beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.

Timing Requirements (Over recommended operating free-air temperature)

| Symbol | Description | $AV_{DD}, V_{DDQ} =$ | Units | | |
|-------------------|--|----------------------|-------|-------|--|
| Symbol | Description | Min. | Max. | Units | |
| f _{CK} | Operating clock frequency ^(1,2) | 60 | 170 | MII- | |
| | Application clock frequency ⁽³⁾ | 95 | 170 | MHz | |
| t _{DC} | Input clock duty cycle | 40 | 60 | % | |
| t _{SIAB} | PLL stabilization time after powerup | | 100 | μs | |

Notes:

1. The PLL is able to handle spread spectrum induced skew.

2. Operating clock frequency indicates a range over which the PLL is able to lock, but in which the clock is not required to meet the other timing parameters. (Used for low-speed debug).

3. Application clock frequency indicates a range over which the PLL meets all of the timing parameters.



DC Specifications Recommended Operating Conditions

| Symbol | Parameter | Min. | Nom. | Max. | Units |
|------------------|--|----------------------------|------|-----------------------|-------|
| AV _{DD} | Analog/core supply voltage | 2.3 | 2.5 | 2.7 | |
| V _{DDQ} | Output supply voltage | 2.3 | 2.5 | 2.7 | |
| V _{OH} | High-level output voltage | 1.8 | | V _{DDQ} | |
| V _{OL} | Low-level output voltage | 0 | | 0.5 | |
| V _{IX} | Input differential-pair crossing voltage | (V _{DDQ} /2) -0.2 | | $(V_{DDQ}/2) + 0.2$ | V |
| V _{OX} | Output differential-pair crossing voltage at the SDRAM clock input | (V _{DDQ} /2) -0.2 | | $(V_{DDQ}/2) + 0.2$ | |
| V _{IN} | Input voltage level | -0.3 | | V _{DDQ} +0.3 | |
| V _{ID} | Input differential voltage between CLK and $\overline{\text{CLK}}$ | 0.36 | | V _{DDQ} +0.6 | |
| V _{OD} | Output differential voltage between $Y[n]$ and $\overline{Y[n]}$ and FBOUT and FBOUT | 0.7 | | V _{DDQ} +0.6 | |
| T _A | Operating free air temperature | 0 | | 70 | °C |

Electrical Characteristics

| Parameter | | Test Conditions | A _{VDD} , V _{DDQ} | Min. | Тур. | Max. | Units |
|------------------|--|--------------------------|-------------------------------------|------|------|------|-------|
| V _{IK} | All inputs | $I_I = -18 \text{mA}$ | 2.3V | | | -1.2 | V |
| II | CLK, FBIN | $V_{I} = V_{DDQ}$ or GND | 2.7V | | | ±10 | μΑ |
| I _{DDQ} | Dynamic supply current of VDDQ | $V_{DD} = 2.7 V^{(1)}$ | | | | 300 | mA |
| I _{ADD} | Dynamic supply current of AV _{DD} | $V_{DD} = 2.7 V^{(1)}$ | | | | 12 | mA |
| C | CLK and CLK | V = V or CND | 2.51 | 2.0 | | 2.0 | жE |
| CI | FBIN and FBIN | $V_{I} = V_{DD}$ or GND | 2.5V | 2.0 | | 3.0 | pF |

Notes:

1. Driving 9 or 18 DDR SDRAM memory chips with 120-ohm termination resistor for each clock output pair at 134 MHz.



AC Specifications

Switching characteristics over recommended operating free-air temperature range, $f_{CLK} > 100$ MHz (unless otherwise noted). (See Figure 1 and 2)

| Description | Description | Diamon | AV _{CC} , | T lasta | | |
|------------------|---|----------------------|--------------------|--------------------|----------------------------|----------|
| Parameter | Description | Diagram | Min. | Nom. | Max | Units |
| t(θ) | Static phase offset ⁽¹⁾ | Figure 4 | -50 | 0 | 50 | |
| tjit(cc) | Cycle-to-cycle jitter | Figure 3 | -75 | | 75 | |
| tjit(per) | Period jitter | Figure 6 | -75 | | 75 | ps |
| tjit(hper) | Half-period jitter | Figure 7 | -100 | | 100 | |
| tsl(i) | Input clock slew rate ⁽²⁾ | Figure 8 | 1.0 | | 2.0 | N // com |
| tsl(o) | Output clock slew rate ⁽²⁾ | Figure 8 | 1.0 | | 2.0 | V/ns |
| tsk(o) | Output clock skew | Figure 5 | | | 100 | ps |
| | | | · | | | |
| The PLL on the P | PI6CV855 meets all the above parameters | while supporting SSC | synthesizers w | vith the following | ng parameters ⁽ | 3). |
| | SSC modulation frequency | | 30.0 | | 50.0 | kHz |
| | SSC clock input frequency deviation | | 0.00 | | -0.50 | % |
| | PLL loop bandwidth | | | 2 | | MHz |
| | Phase angle | | | | -0.031 | degrees |

Notes:

1. Static Phase offset does not include jitter.

2. The slew rate is determined from the IBIS model with test load shown in Figure 1.

3. The SSC requirements meet the Intel PC100 SDRAM Registered DIMM specification.





Figure 1. IBIS Model Output Load



Figure 2. Output Load Test Circuit





Figure 3. Cycle-to-Cycle Jitter



Figure 4. Static Phase Offset



Figure 5. Output Skew





Figure 6. Period Jitter



Figure 7. Half-Period Jitter



Figure 8. Input and Output Slew Rates



Packaging Mechanical: 28-Pin TSSOP(L)



Ordering Information

| Ordering Code | Package Code | Package Type |
|----------------------|---------------------|--|
| PI6CV855L | L | 28-pin 173-mil wide TSSOP |
| PI6CV855LE | L | Pb-free & Green, 28-pin 173-mil wide TSSOP |

Notes:

1. Thermal characteristics can be found on the company web site at www.pericom.com/packaging/